



# 23<sup>rd</sup> IEEE European Test Symposium

Swissôtel Bremen

Bremen, Germany | May 28 – June 01, 2018

[www.ets18.de](http://www.ets18.de)



## CALL FOR PARTICIPATION

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuit and system testing and reliability as well as in the fields of verification and security aspects in test. In 2018, ETS will take place at Swissôtel, Bremen, Germany. It is organized by the University of Bremen, which co-sponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). ETS traditionally enjoys a strong balance among academic and industrial participants. In addition to regular Scientific Papers, Special Sessions, Panels, and Embedded Tutorials, ETS features Vendor Sessions and Table-Top Demos as well as a special track on Emerging Test Strategies (ETS<sup>2</sup>) where new issues are presented by the industry and are discussed in an informal atmosphere. ETS is the major event of the European Test Week, which includes TSS (Test Spring School) and fringe workshops.

### General Chairs

Stephan Eggersglüß (DE)  
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Paolo Bernardi (IT), Christoph Scholl (DE), Said Hamdioui (NL), Krish Chakrabarty (US), Patrick Girard (FR), Erik Larsson (SE), Gildas Léger (ES), Michael Maniatakos (AE), Adit Singh (US), Iliia Polian (DE), Jochen Rivoir (DE)

### ETS<sup>2</sup> Chairs

Rene Segers (NL), Zebo Peng (SE)

### Panel Chairs

Xinli Gu (US), Mehdi Tahoori (DE)

### Embedded Tutorial Chairs

Teresa McLaurin (US), Maria Michael (CY)

### Special Session Chairs

Stephen Sunter (CAN), Jerzy Tyszer (PL)

### Industrial Relations Chairs

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### Publication Chairs

Giorgio Di Natale (FR)

Alberto Bosio (FR)

### Web & Electronic Media Chairs

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Stefano Di Carlo (IT)

### Publicity Chairs

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Michiko Inoue (JP)

Ioannis Voyatzis (GR)

### Award Chairs

Sybille Hellebrand (DE)

Peter Maxwell (US)

### ETS Fringe Workshops

Iliia Polian (DE)

Maksim Jenihhin (EE)

### Regional Liaisons

Shi-Yu Huang (TW)

Fernanda Lima Kastensmidt (BR)

Adam Osseiran (AUS)

Nicola Nicolici (CAN)

Ashraf Farghaly Salem (EG)

### Local & Financial Chair

Sebastian Huhn (DE)

### TSS (Test Spring School) Chairs

Lorena Anghel (FR)

Hans-Joachim Wunderlich (DE)

### TSS Local Chair

Görschwin Fey (DE)

### Steering Committee

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## KEYNOTES

**Riccardo Mariani, Intel: Making the autonomous dream work**

**Janusz Rajski, Mentor: Automotive ICs –the key driver of innovation in test**

**Jan Peleska, University of Bremen: Model-based Avionic Systems Testing for the Airbus Family**

### Regular Paper Sessions

- Analog, Mixed-Signal, and RF
- Security and Trust
- System Control and Test
- Latches and Memories
- Test for Advanced Fault Models

### Embedded Tutorials

- Design and Testing Methodologies for True Random Number Generators – Towards Industry Cert.
- Machine Design of Fault-Tolerant Neuromorphic Computing Systems
- Machine Learning Applications in Test

### Special Sessions

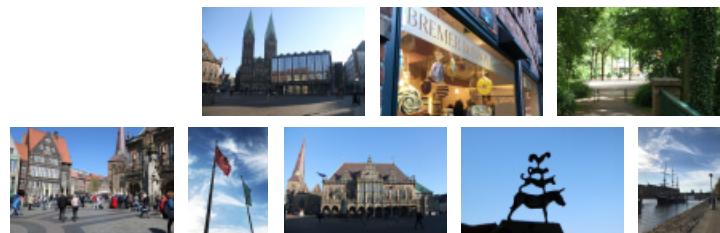
- Device Aging: Security and Reliability Concerns in Emerging technologies
- Zero DPPM
- Functional Safety and Test

### Panels

- The future of test (community): Town Hall Meeting
- Auto-driving, Machine Learning and Test

### ETS<sup>2</sup>

- How to get the required Quality and Reliability at reasonable (test)costs?
- Test data sharing between the various stakeholders in the IC supply chain
- Online test coverage approaches compared to (initial) manufacturing test coverage
- Update on the AMS initiative originated at the ETS<sup>2</sup> in Paderborn (2014).



### Fringe Workshops

- TESTA'18: 3rd International Test Standards Application Workshop
- SURREALIST: Workshop on SecURity, REliAbiLty, test, prlvacy, Safety and Trust of Future Devices
- AxC: Workshop on Approximate Computing

Interested researchers are invited to participate at the symposium. Details on the registration can be found at [www.ets18.de](http://www.ets18.de). The registration fee includes a digital copy of the proceedings, lunches and coffee breaks for all days, as well as the excursion and banquet the evening of Wednesday May 30th.

Further Information:

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